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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

AKRAM ALI SALMAN
XUEJUN ZHAO
KURT O. TAYLOR
STEPHEN G. BEEBE

Examiner: Laura M. Schillinger

Group Art Unit: 2813

Att'y Docket: 2000.111200/H2022

Customer No.: 23720

Serial No.: 10/664,665

Filed: September 18, 2003

For: METHOD FOR DETERMINING THE
RELIABILITY OF DIELECTRIC
LAYERS

ENTERED
By
RCE
FILED
10-11-05

RESPONSE TO FINAL OFFICE ACTION DATED JULY 12, 2005

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

CERTIFICATE OF MAILING 37 C.F.R. 1.8	
I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:	
September 12, 2005 Date	<i>Max Paul</i> Signature

This paper is submitted in response to the Final Office Action dated July 12, 2005, for which the three-month date for response is October 12, 2005.

No fees are believed to be due in connection with the present paper. However, should any fees be required under 37 C.F.R. §§ 1.16 to 1.21, the Director is authorized to deduct such fees from the Advanced Micro Devices, Inc. Deposit Account No. 01-0365/H2022. In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.111200.

Reconsideration of the application in view of the following amendments and remarks is respectfully requested.